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U.S. **UTILITY** Patent Application

O.I.P.E. SCANNED

APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT **EXAMINER** 09/662409 D -019 3729 STARSIAK 604 204 JEFFREY A. WOLK

1743

HIGH-THROUGHPUT ANALYTICAL MICROFLUIDIC SYSTEMS AND METHODS OF MAKING SAME

ISSUING CLASSIFICATION								
ORIGINA	AL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
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INTERNATIONAL CLASSIFICATION								
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TERMINAL	DRAWINGS			CLAIMS ALLOWED	
□ DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G
☐ The term of this patent subsequent to(date)				NOTICE OF ALLOWANCE MAILED	
has been disclaimed.	(Assistant Examiner) (Date)		•		
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